

Notice of References Cited	Application/Control No. 10/723,283	Applicant(s)/Patent Under Reexamination FABRITIUS, HENNA	
	Examiner Jinhee J. Lee	Art Unit 2175	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,513,309	04-1996	Meier et al.	715/860
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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